

# Evaluation of fluence dependent variations of capacitance and generation current parameters by transient technique

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A transient technique for barrier evaluation by linearly increased voltage (BELIV) is presented. Variations of current transients under reverse and forward LIV biased pad-detectors, irradiated by reactor neutrons with fluences in the range of  $10^{12}$  -  $10^{16}$  cm<sup>-2</sup>, are analyzed. Correlations between the BELIV and impedance based C-V measurements are discussed.

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